Notice of References Cited

		<u>/</u>	
Application/Control No.		Applicant(s)/Pater	nt Under
10/034,320		Reexamination PARK ET AL.	
Examiner	-	Art Unit	
Granvill D Lee, Jr		2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6034539	03-2000	Hwang	326/38
	В	US-5880596	03-1999	White	326/38
	С	US-5051615	09-1991	Rosenthal	307/350
	D	US-6427222	07-2002	Shau	716/4
	E	US-6426560	07-2002	Kawamura et al.	257/777
	F	US-5568610	10-1996	Brown	395/185.01
	G	US-5768173	06-1998	Seo et al.	365/52
	Н	US-5767583	06-1998	Lee et al.	257/786
	ı	US-6366487	04-2002	Yeom	365/52
	J	US-2002/0009006	01-2002	Saitoh et al.	365/201
	к	US-6551846	04-2003	Furutani et al.	438/17
	L	US-5920227	07-1999	An	327/544
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	2000-11641	01-2000	JPO		G11C 11/401
	0	9-185898	07-1997	JPO		G11C 29/00
	Р					
	Q					
	R					
	s					
	Т		<u> </u>			

NON-PATENT DOCUMENTS

*	[Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	,
	v	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.